Issue Classification			Applicant(s)reate	Applicant(s)/Patent under Keexamination	lon
	10038165		BURTON ET AL.		
	Examiner		Art Unit		
	Betit, Jacob F		2164		
ORIGINAL	IAL	INTE	ERNATIONAL	INTERNATIONAL CLASSIFICATION	N
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CROSS REFERENCE(S)	ZENCE(S)			٠	
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Jecob F Betit	90			Total Claims Allowed:	: Allowed:
(Assistant Examiner) (Date)					
	Sam Rimell	July Jul 06		0.G. Print Claim(s)	O.G. Print Figure
(Legal Instruments Examiner) (Date)	(Primary Examiner)	SAM RIMELL (Date)		-	~

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